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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	320
Number of Logic Elements/Cells	-
Total RAM Bits	64160
Number of I/O	70
Number of Gates	6000
Voltage - Supply	3V ~ 3.6V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	84-LCC (J-Lead)
Supplier Device Package	84-PLCC (29.31x29.31)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc3090l-8pc84i

Detailed Functional Description

The perimeter of configurable Input/Output Blocks (IOBs) provides a programmable interface between the internal logic array and the device package pins. The array of Configurable Logic Blocks (CLBs) performs user-specified logic functions. The interconnect resources are programmed to form networks, carrying logic signals among blocks, analogous to printed circuit board traces connecting MSI/SSI packages.

The block logic functions are implemented by programmed look-up tables. Functional options are implemented by program-controlled multiplexers. Interconnecting networks between blocks are implemented with metal segments joined by program-controlled pass transistors.

These FPGA functions are established by a configuration program which is loaded into an internal, distributed array of configuration memory cells. The configuration program is loaded into the device at power-up and may be reloaded on command. The FPGA includes logic and control signals to implement automatic or passive configuration. Program

data may be either bit serial or byte parallel. The development system generates the configuration program bitstream used to configure the device. The memory loading process is independent of the user logic functions.

Configuration Memory

The static memory cell used for the configuration memory in the Field Programmable Gate Array has been designed specifically for high reliability and noise immunity. Integrity of the device configuration memory based on this design is assured even under adverse conditions. As shown in [Figure 3](#), the basic memory cell consists of two CMOS inverters plus a pass transistor used for writing and reading cell data. The cell is only written during configuration and only read during readback. During normal operation, the cell provides continuous control and the pass transistor is off and does not affect cell stability. This is quite different from the operation of conventional memory devices, in which the cells are frequently read and rewritten.

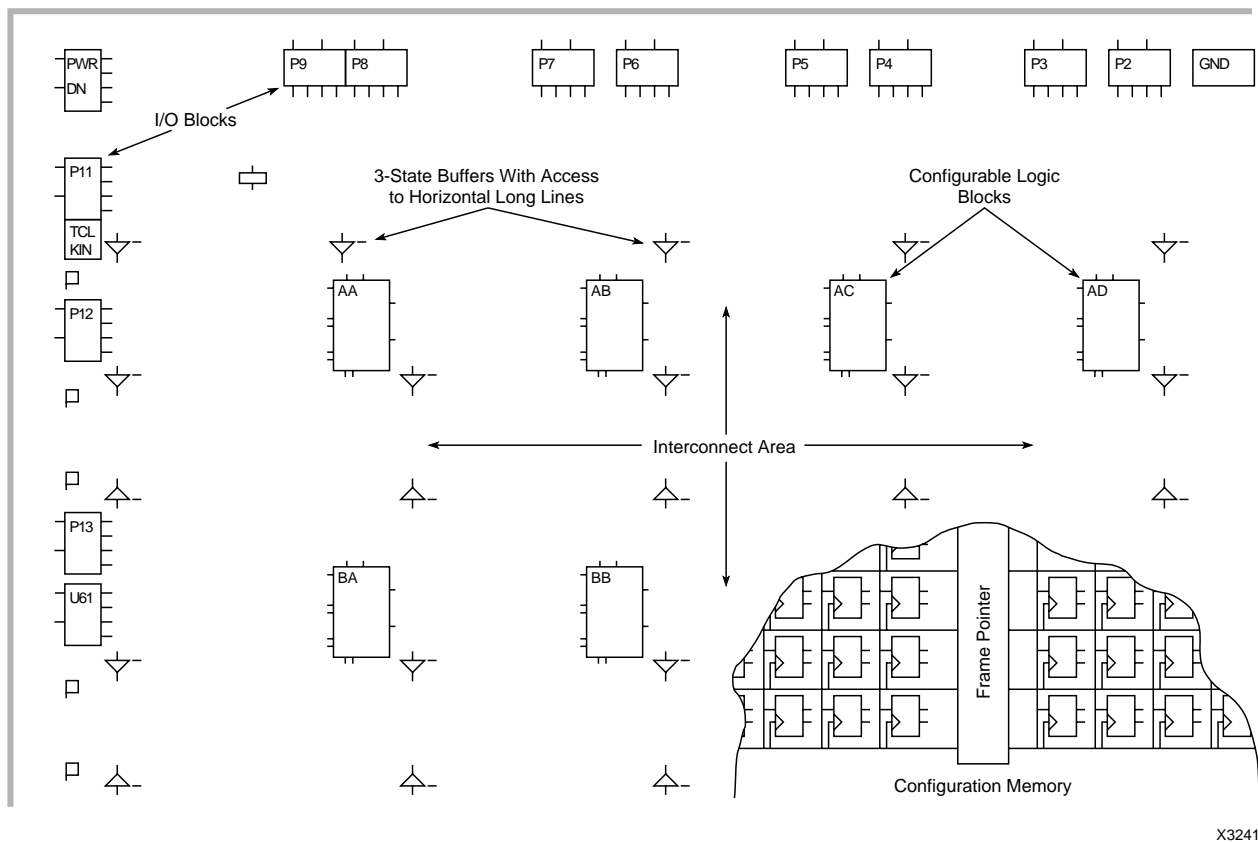


Figure 2: Field Programmable Gate Array Structure.

It consists of a perimeter of programmable I/O blocks, a core of configurable logic blocks and their interconnect resources. These are all controlled by the distributed array of configuration program memory cells.

Longlines

The Longlines bypass the switch matrices and are intended primarily for signals that must travel a long distance, or must have minimum skew among multiple destinations. Longlines, shown in Figure 14, run vertically and horizontally the height or width of the interconnect area. Each interconnection column has three vertical Longlines, and each interconnection row has two horizontal Longlines. Two additional Longlines are located adjacent to the outer sets of switching matrices. In devices larger than the XC3020A and XC3120A FPGAs, two vertical Longlines in each col-

umn are connectable half-length lines. On the XC3020A and XC3120A FPGAs, only the outer Longlines are connectable half-length lines.

Longlines can be driven by a logic block or IOB output on a column-by-column basis. This capability provides a common low skew control or clock line within each column of logic blocks. Interconnections of these Longlines are shown in Figure 15. Isolation buffers are provided at each input to a Longline and are enabled automatically by the development system when a connection is made.

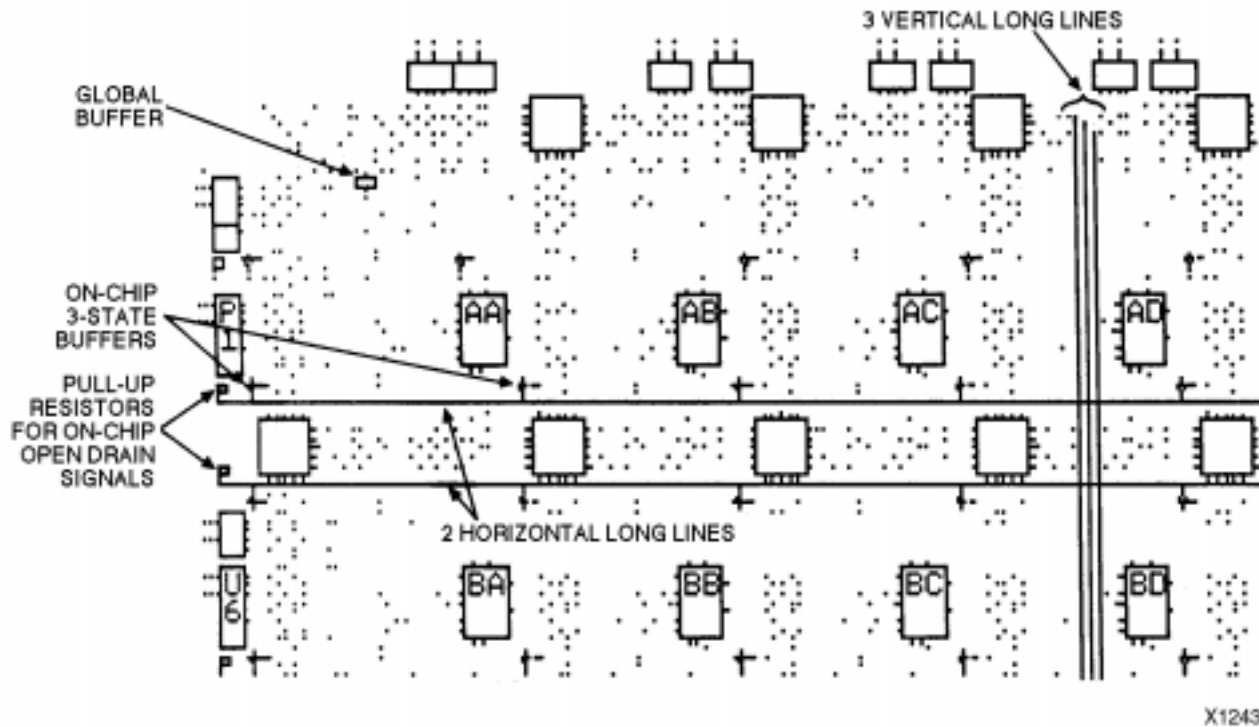


Figure 14: Horizontal and Vertical Longlines. These Longlines provide high fan-out, low-skew signal distribution in each row and column. The global buffer in the upper left die corner drives a common line throughout the FPGA.

Peripheral Mode

Peripheral mode uses the trailing edge of the logic AND condition of the $\overline{CS0}$, $\overline{CS1}$, $\overline{CS2}$, and \overline{WS} inputs to accept byte-wide data from a microprocessor bus. In the lead FPGA, this data is loaded into a double-buffered UART-like parallel-to-serial converter and is serially shifted into the internal logic. The lead FPGA presents the preamble data (and all data that overflows the lead device) on the DOUT pin.

The Ready/Busy output from the lead device acts as a handshake signal to the microprocessor. $\overline{RDY/BUSY}$ goes Low when a byte has been received, and goes High again

when the byte-wide input buffer has transferred its information into the shift register, and the buffer is ready to receive new data. The length of the \overline{BUSY} signal depends on the activity in the UART. If the shift register had been empty when the new byte was received, the \overline{BUSY} signal lasts for only two CCLK periods. If the shift register was still full when the new byte was received, the \overline{BUSY} signal can be as long as nine CCLK periods.

Note that after the last byte has been entered, only seven of its bits are shifted out. CCLK remains High with DOUT equal to bit 6 (the next-to-last bit) of the last byte entered.

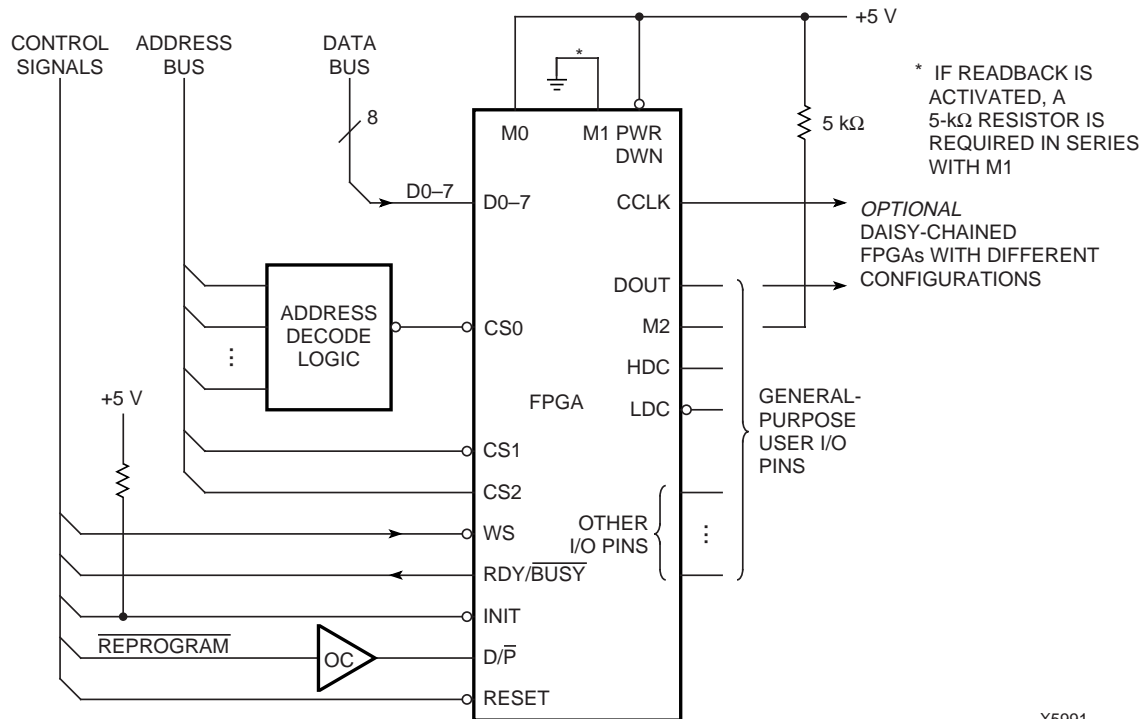


Figure 27: Peripheral Mode Circuit Diagram

Slave Serial Mode

In Slave Serial mode, an external signal drives the CCLK input(s) of the FPGA(s). The serial configuration bitstream must be available at the DIN input of the lead FPGA a short set-up time before each rising CCLK edge. The lead device then presents the preamble data (and all data that over-

flows the lead device) on its DOUT pin. There is an internal delay of 0.5 CCLK periods, which means that DOUT changes on the falling CCLK edge, and the next device in the daisy-chain accepts data on the subsequent rising CCLK edge.

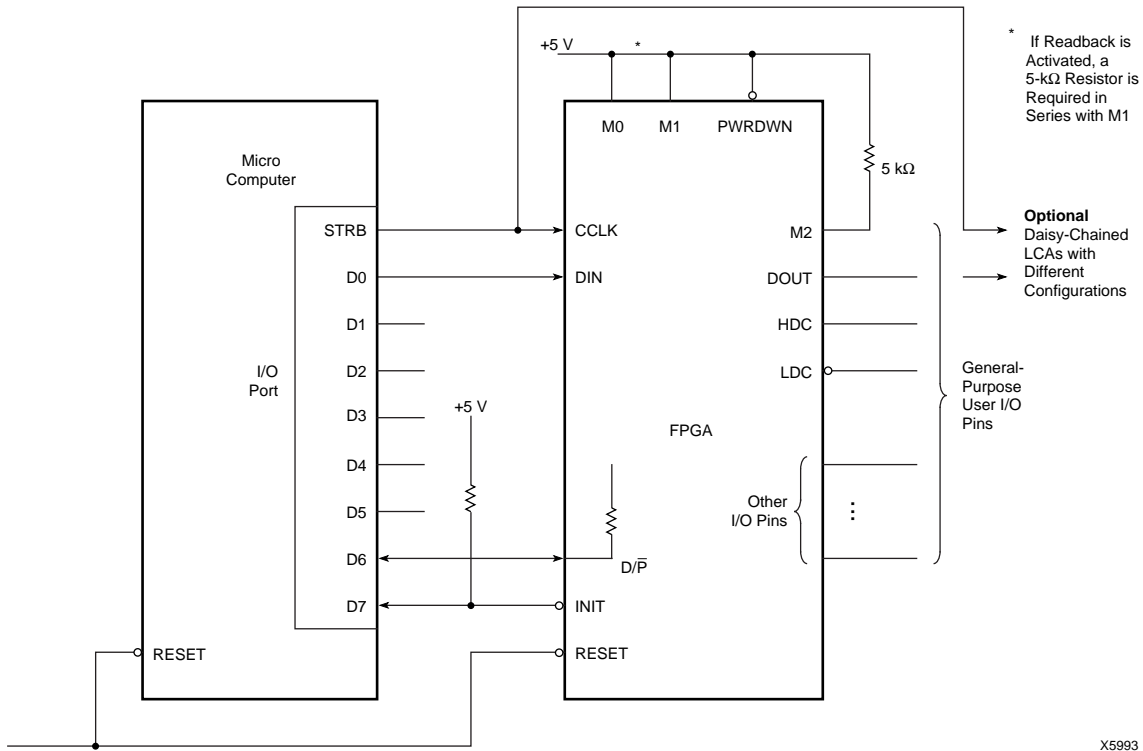


Figure 29: Slave Serial Mode Circuit Diagram

Dynamic Power Consumption

	XC3042A	XC3042L	XC3142A	
One CLB driving three local interconnects	0.25	0.17	0.25	mW per MHz
One global clock buffer and clock line	2.25	1.40	1.70	mW per MHz
One device output with a 50 pF load	1.25	1.25	1.25	mW per MHz

Power Consumption

The Field Programmable Gate Array exhibits the low power consumption characteristic of CMOS ICs. For any design, the configuration option of TTL chip input threshold requires power for the threshold reference. The power required by the static memory cells that hold the configuration data is very low and may be maintained in a power-down mode.

Typically, most of power dissipation is produced by external capacitive loads on the output buffers. This load and frequency dependent power is 25 μ W/pF/MHz per output. Another component of I/O power is the external dc loading on all output pins.

Internal power dissipation is a function of the number and size of the nodes, and the frequency at which they change. In an FPGA, the fraction of nodes changing on a given clock is typically low (10-20%). For example, in a long binary counter, the total activity of all counter flip-flops is equivalent to that of only two CLB outputs toggling at the clock frequency. Typical global clock-buffer power is between 2.0 mW/MHz for the XC3020A and 3.5 mW/MHz for the XC3090A. The internal capacitive load is more a function of interconnect than fan-out. With a typical load of three general interconnect segments, each CLB output requires about 0.25 mW per MHz of its output frequency.

Because the control storage of the FPGA is CMOS static memory, its cells require a very low standby current for data retention. In some systems, this low data retention current characteristic can be used as a method of preserving configurations in the event of a primary power loss. The FPGA

has built in powerdown logic which, when activated, will disable normal operation of the device and retain only the configuration data. All internal operation is suspended and output buffers are placed in their high-impedance state with no pull-ups. Different from the XC3000 family which can be powered down to a current consumption of a few microamps, the XC3100A draws 5 mA, even in power-down. This makes power-down operation less meaningful. In contrast, I_{CCPD} for the XC3000L is only 10 μ A.

To force the FPGA into the Powerdown state, the user must pull the PWRDWN pin Low and continue to supply a retention voltage to the V_{CC} pins. When normal power is restored, V_{CC} is elevated to its normal operating voltage and PWRDWN is returned to a High. The FPGA resumes operation with the same internal sequence that occurs at the conclusion of configuration. Internal-I/O and logic-block storage elements will be reset, the outputs will become enabled and the DONE/ \overline{PROG} pin will be released.

When V_{CC} is shut down or disconnected, some power might unintentionally be supplied from an incoming signal driving an I/O pin. The conventional electrostatic input protection is implemented with diodes to the supply and ground. A positive voltage applied to an input (or output) will cause the positive protection diode to conduct and drive the V_{CC} connection. This condition can produce invalid power conditions and should be avoided. A large series resistor might be used to limit the current or a bipolar buffer may be used to isolate the input signal.

Pin Descriptions

Permanently Dedicated Pins

V_{CC}

Two to eight (depending on package type) connections to the positive V supply voltage. All must be connected.

GND

Two to eight (depending on package type) connections to ground. All must be connected.

\overline{PWRDWN}

A Low on this CMOS-compatible input stops all internal activity, but retains configuration. All flip-flops and latches are reset, all outputs are 3-stated, and all inputs are interpreted as High, independent of their actual level. When \overline{PWRDWN} returns High, the FPGA becomes operational with \overline{DONE} Low for two cycles of the internal 1-MHz clock. Before and during configuration, \overline{PWRDWN} must be High. If not used, \overline{PWRDWN} must be tied to V_{CC} .

\overline{RESET}

This is an active Low input which has three functions.

Prior to the start of configuration, a Low input will delay the start of the configuration process. An internal circuit senses the application of power and begins a minimal time-out cycle. When the time-out and \overline{RESET} are complete, the levels of the M lines are sampled and configuration begins.

If \overline{RESET} is asserted during a configuration, the FPGA is re-initialized and restarts the configuration at the termination of \overline{RESET} .

If \overline{RESET} is asserted after configuration is complete, it provides a global asynchronous \overline{RESET} of all IOB and CLB storage elements of the FPGA.

CCLK

During configuration, Configuration Clock is an output of an FPGA in Master mode or Peripheral mode, but an input in Slave mode. During Readback, CCLK is a clock input for shifting configuration data out of the FPGA.

CCLK drives dynamic circuitry inside the FPGA. The Low time may, therefore, not exceed a few microseconds. When used as an input, CCLK must be "parked High". An internal pull-up resistor maintains High when the pin is not being driven.

$\overline{DONE/PROG (D/P)}$

\overline{DONE} is an open-drain output, configurable with or without an internal pull-up resistor of 2 to 8 k Ω . At the completion of configuration, the FPGA circuitry becomes active in a synchronous order; \overline{DONE} is programmed to go active High one cycle either before or after the outputs go active.

Once configuration is done, a High-to-Low transition of this pin will cause an initialization of the FPGA and start a reconfiguration.

M0/RTRIG

As Mode 0, this input is sampled on power-on to determine the power-on delay (2^{14} cycles if M0 is High, 2^{16} cycles if M0 is Low). Before the start of configuration, this input is again sampled together with M1, M2 to determine the configuration mode to be used.

A Low-to-High input transition, after configuration is complete, acts as a Read Trigger and initiates a Readback of configuration and storage-element data clocked by CCLK. By selecting the appropriate Readback option when generating the bitstream, this operation may be limited to a single Readback, or be inhibited altogether.

$\overline{M1/RDATA}$

As Mode 1, this input and M0, M2 are sampled before the start of configuration to establish the configuration mode to be used. If Readback is never used, M1 can be tied directly to ground or V_{CC} . If Readback is ever used, M1 must use a 5-k Ω resistor to ground or V_{CC} , to accommodate the RDATA output.

As an active-Low Read Data, after configuration is complete, this pin is the output of the Readback data.

User I/O Pins That Can Have Special Functions

M2

During configuration, this input has a weak pull-up resistor. Together with M0 and M1, it is sampled before the start of configuration to establish the configuration mode to be used. After configuration, this pin is a user-programmable I/O pin.

HDC

During configuration, this output is held at a High level to indicate that configuration is not yet complete. After configuration, this pin is a user-programmable I/O pin.

\overline{LDC}

During Configuration, this output is held at a Low level to indicate that the configuration is not yet complete. After configuration, this pin is a user-programmable I/O pin. \overline{LDC} is particularly useful in Master mode as a Low enable for an EPROM, but it must then be programmed as a High after configuration.

\overline{INIT}

This is an active Low open-drain output with a weak pull-up and is held Low during the power stabilization and internal clearing of the configuration memory. It can be used to indicate status to a configuring microprocessor or, as a wired

XC3000A Absolute Maximum Ratings

Symbol	Description		Units
V_{CC}	Supply voltage relative to GND	–0.5 to +7.0	V
V_{IN}	Input voltage with respect to GND	–0.5 to $V_{CC} + 0.5$	V
V_{TS}	Voltage applied to 3-state output	–0.5 to $V_{CC} + 0.5$	V
T_{STG}	Storage temperature (ambient)	–65 to +150	°C
T_{SOL}	Maximum soldering temperature (10 s @ 1/16 in.)	+260	°C
T_J	Junction temperature plastic	+125	°C
	Junction temperature ceramic	+150	°C

Note: Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those listed under Recommended Operating Conditions is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time may affect device reliability.

XC3000A Global Buffer Switching Characteristics Guidelines

		Speed Grade	-7	-6	
Description	Symbol		Max	Max	Units
Global and Alternate Clock Distribution ¹ Either: Normal IOB input pad through clock buffer to any CLB or IOB clock input Or: Fast (CMOS only) input pad through clock buffer to any CLB or IOB clock input	T_{PID}		7.5	7.0	ns
	T_{PIDC}		6.0	5.7	ns
TBUF driving a Horizontal Longline (L.L.) ¹ I to L.L. while T is Low (buffer active) T↓ to L.L. active and valid with single pull-up resistor T↓ to L.L. active and valid with pair of pull-up resistors T↑ to L.L. High with single pull-up resistor T↑ to L.L. High with pair of pull-up resistors	T_{IO} T_{ON} T_{ON} T_{PUS} T_{PUF}		4.5 9.0 11.0 16.0 10.0	4.0 8.0 10.0 14.0 8.0	ns ns ns ns ns
BIDI Bidirectional buffer delay	T_{BIDI}		1.7	1.5	ns

Note: 1. Timing is based on the XC3042A, for other devices see timing calculator.

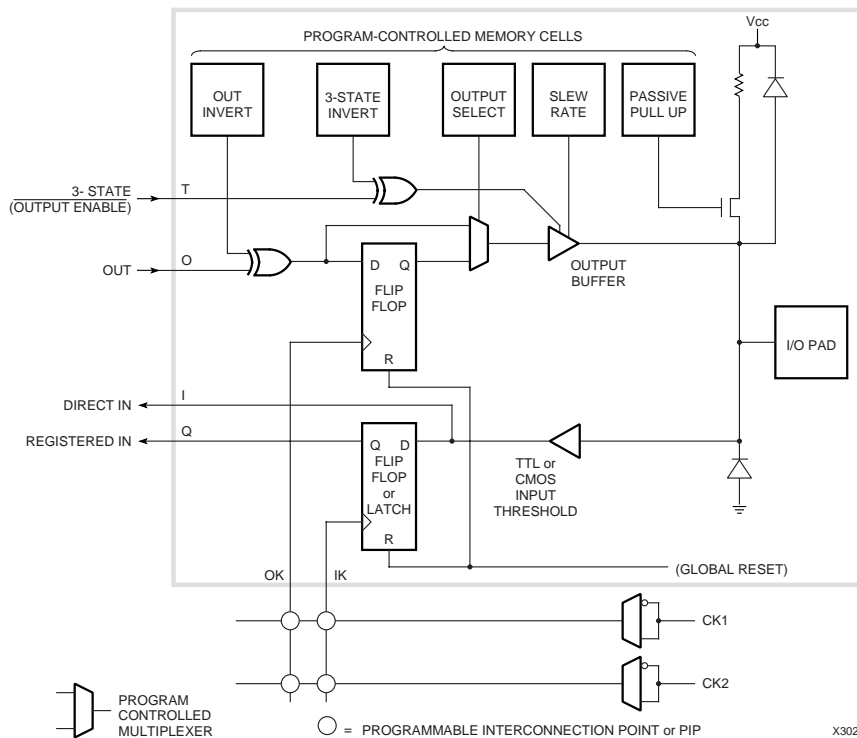
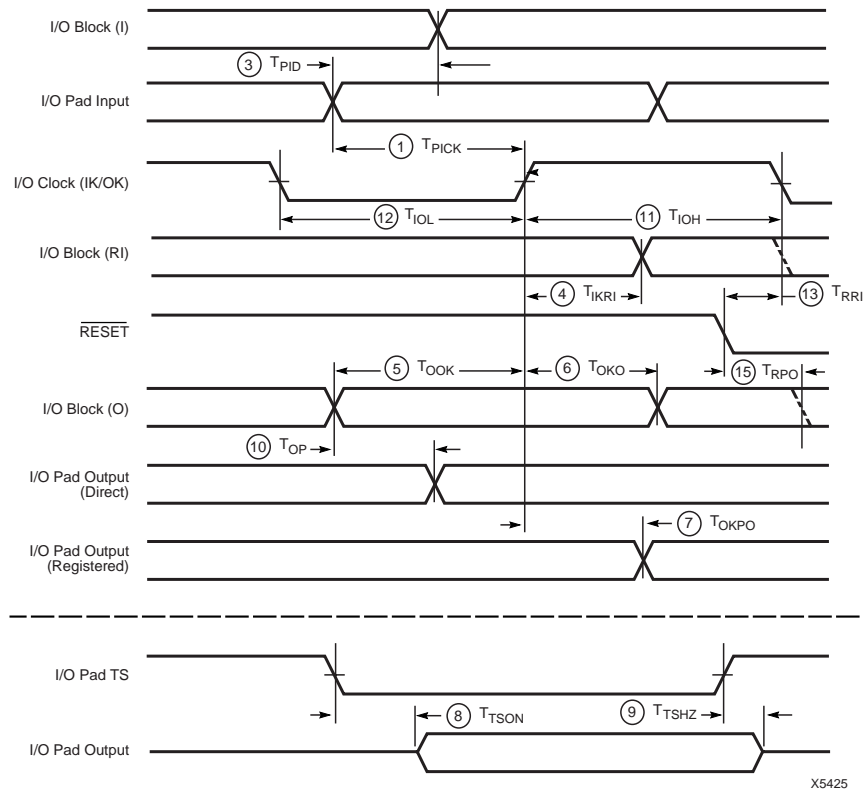
XC3000A CLB Switching Characteristics Guidelines

Testing of the switching parameters is modeled after testing methods specified by MIL-M-38510/605. All devices are 100% functionally tested. Since many internal timing parameters cannot be measured directly, they are derived from benchmark timing patterns. The following guidelines reflect worst-case values over the recommended operating conditions. For more detailed, more precise, and more up-to-date timing information, use the values provided by the timing calculator and used in the simulator.

		Speed Grade		-7		-6		
Description		Symbol		Min	Max	Min	Max	Units
Combinatorial Delay Logic Variables A, B, C, D, E, to outputs X or Y FG Mode F and FGM Mode		1	T_{ILO}		5.1 5.6		4.1 4.6	ns ns
	Sequential delay Clock k to outputs X or Y	8	T_{CKO}		4.5		4.0	ns
	Clock k to outputs X or Y when Q is returned through function generators F or G to drive X or Y FG Mode F and FGM Mode		T_{QLO}		9.5 10.0		8.0 8.5	ns ns
Set-up time before clock K Logic Variables A, B, C, D, E FG Mode F and FGM Mode		2	T_{ICK}	4.5 5.0		3.5 4.0		ns ns
	Data In DI	4	T_{DICK}	4.0		3.0		ns
	Enable Clock EC	6	T_{ECKK}	4.5		4.0		ns
Hold Time after clock K Logic Variables A, B, C, D, E Data In DI ² Enable Clock EC		3	T_{CKI}	0		0		ns
		5	T_{CKDI}	1.0		1.0		ns
		7	T_{CKEC}	2.0		2.0		ns
Clock Clock High time Clock Low time Max. flip-flop toggle rate		11	T_{CH}	4.0		3.5		ns
		12	T_{CL}	4.0		3.5		ns
			F_{CLK}	113.0		135.0		MHz
Reset Direct (RD) RD width delay from RD to outputs X or Y		13	T_{RPW}	6.0		5.0		ns
		9	T_{RIO}		6.0		5.0	ns
Global Reset (RESET Pad) ¹ RESET width (Low) delay from RESET pad to outputs X or Y			T_{MRW}	16.0		14.0		ns
			T_{MRQ}		19.0		17.0	ns

- Notes:**
1. Timing is based on the XC3042A, for other devices see timing calculator.
 2. The CLB K to Q output delay (T_{CKO} , #8) of any CLB, plus the shortest possible interconnect delay, is always longer than the Data In hold time requirement (T_{CKDI} , #5) of any CLB on the same die.

XC3000A IOB Switching Characteristics Guidelines (continued)



XC3000L Switching Characteristics

Xilinx maintains test specifications for each product as controlled documents. To insure the use of the most recently released device performance parameters, please request a copy of the current test-specification revision.

XC3000L Operating Conditions

Symbol	Description	Min	Max	Units
V_{CC}	Supply voltage relative to GND Commercial 0°C to +85°C junction	3.0	3.6	V
V_{IH}	High-level input voltage — TTL configuration	2.0	$V_{CC}+0.3$	V
V_{IL}	Low-level input voltage — TTL configuration	-0.3	0.8	V
T_{IN}	Input signal transition time		250	ns

- Notes:**
1. At junction temperatures above those listed as Operating Conditions, all delay parameters increase by 0.3% per °C.
 2. Although the present (1996) devices operate over the full supply voltage range from 3.0 to 5.25 V, Xilinx reserves the right to restrict operation to the 3.0 to 3.6 V range later, when smaller device geometries might preclude operation at 5V. Operating conditions are guaranteed in the 3.0 – 3.6 V V_{CC} range.

XC3000L DC Characteristics Over Operating Conditions

Symbol	Description	Min	Max	Units
V_{OH}	High-level output voltage (@ $I_{OH} = -4.0$ mA, V_{CC} min)	2.40		V
V_{OL}	Low-level output voltage (@ $I_{OL} = 4.0$ mA, V_{CC} min)		0.40	V
V_{OH}	High-level output voltage (@ $I_{OH} = -4.0$ mA, V_{CC} min)	$V_{CC} - 0.2$		V
V_{OL}	Low-level output voltage (@ $I_{OL} = 4.0$ mA, V_{CC} min)		0.2	V
V_{CCPD}	Power-down supply voltage (PWRDWN must be Low)	2.30		V
I_{CCPD}	Power-down supply current ($V_{CC(MAX)}$ @ T_{MAX})		10	μA
I_{CCO}	Quiescent FPGA supply current in addition to I_{CCPD} ¹ Chip thresholds programmed as CMOS levels		20	μA
I_{IL}	Input Leakage Current	-10	+10	μA
C_{IN}	Input capacitance, all packages except PGA175 (sample tested) All Pins except XTL1 and XTL2		10	pF
	XTL1 and XTL2		15	pF
	Input capacitance, PGA 175 (sample tested) All Pins except XTL1 and XTL2		15	pF
	XTL1 and XTL2		20	pF
I_{RIN}	Pad pull-up (when selected) @ $V_{IN} = 0$ V ³	0.01	0.17	mA
I_{RLL}	Horizontal Longline pull-up (when selected) @ logic Low		2.50	mA

- Notes:**
1. With no output current loads, no active input or Longline pull-up resistors, all package pins at V_{CC} or GND, and the FPGA device configured with a tie option. I_{CCO} is in addition to I_{CCPD} .
 2. Total continuous output sink current may not exceed 100 mA per ground pin. Total continuous output source may not exceed 100 mA per V_{CC} pin. The number of ground pins varies from the XC3020L to the XC3090L.
 3. Not tested. Allows an undriven pin to float High. For any other purpose, use an external pull-up.

XC3000L IOB Switching Characteristics Guidelines

Testing of the switching parameters is modeled after testing methods specified by MIL-M-38510/605. All devices are 100% functionally tested. Since many internal timing parameters cannot be measured directly, they are derived from benchmark timing patterns. The following guidelines reflect worst-case values over the recommended operating conditions. For more detailed, more precise, and more up-to-date timing information, use the values provided by the timing calculator and used in the simulator.

Description	Speed Grade		-8		Units
	Symbol		Min	Max	
Propagation Delays (Input)					
Pad to Direct In (I)	3	T_{PID}		5.0	ns
Pad to Registered In (Q) with latch transparent		T_{PTG}		24.0	ns
Clock (IK) to Registered In (Q)	4	T_{IKRI}		6.0	ns
Set-up Time (Input)					
Pad to Clock (IK) set-up time	1	T_{PICK}	22.0		ns
Propagation Delays (Output)					
Clock (OK) to Pad (fast)	7	T_{OKPO}		12.0	ns
same (slew rate limited)	7	T_{OKPO}		28.0	ns
Output (O) to Pad (fast)	10	T_{OPF}		9.0	ns
same (slew-rate limited)	10	T_{OPS}		25.0	ns
3-state to Pad begin hi-Z (fast)	9	T_{TSHZ}		12.0	ns
same (slew-rate limited)	9	T_{TSHZ}		28.0	ns
3-state to Pad active and valid (fast)	8	T_{TSOIN}		16.0	ns
same (slew -rate limited)	8	T_{TSOIN}		32.0	ns
Set-up and Hold Times (Output)					
Output (O) to clock (OK) set-up time	5	T_{OOK}	12.0		ns
Output (O) to clock (OK) hold time	6	T_{OKO}	0		ns
Clock					
Clock High time	11	T_{IOH}	5.0		ns
Clock Low time	12	T_{IOL}	5.0		ns
Max. flip-flop toggle rate		F_{CLK}	80.0		MHz
Global Reset Delays (based on XC3042L)					
\overline{RESET} Pad to Registered In (Q)	13	T_{RRI}		25.0	ns
\overline{RESET} Pad to output pad (fast)	15	T_{RPO}		35.0	ns
(slew-rate limited)	15	T_{RPO}		51.0	ns

- Notes:**
1. Timing is measured at pin threshold, with 50 pF external capacitive loads (incl. test fixture). Typical slew rate limited output rise/fall times are approximately four times longer.
 2. Voltage levels of unused (bonded and unbonded) pads must be valid logic levels. Each can be configured with the internal pull-up resistor or alternatively configured as a driven output or driven from an external source.
 3. Input pad set-up time is specified with respect to the internal clock (ik). In order to calculate system set-up time, subtract clock delay (pad to ik) from the input pad set-up time value. Input pad holdtime with respect to the internal clock (ik) is negative. This means that pad level changes immediately before the internal clock edge (ik) will not be recognized.
 4. T_{PID} , T_{PTG} , and T_{PICK} are 3 ns higher for XTL2 when the pin is configured as a user input.

XC3100A Switching Characteristics

Xilinx maintains test specifications for each product as controlled documents. To insure the use of the most recently released device performance parameters, please request a copy of the current test-specification revision.

XC3100A Operating Conditions

Symbol	Description	Min	Max	Units
V_{CC}	Supply voltage relative to GND Commercial 0°C to +85°C junction	4.25	5.25	V
	Supply voltage relative to GND Industrial -40°C to +100°C junction	4.5	5.5	V
V_{IHT}	High-level input voltage — TTL configuration	2.0	V_{CC}	V
V_{ILT}	Low-level input voltage — TTL configuration	0	0.8	V
V_{IHC}	High-level input voltage — CMOS configuration	70%	100%	V_{CC}
V_{ILC}	Low-level input voltage — CMOS configuration	0	20%	V_{CC}
T_{IN}	Input signal transition time		250	ns

Note: At junction temperatures above those listed as Operating Conditions, all delay parameters increase by 0.3% per °C.

XC3100A DC Characteristics Over Operating Conditions

Symbol	Description	Min	Max	Units
V_{OH}	High-level output voltage (@ $I_{OH} = -8.0$ mA, V_{CC} min)	3.86		V
V_{OL}	Low-level output voltage (@ $I_{OL} = 8.0$ mA, V_{CC} min)		0.40	V
V_{OH}	High-level output voltage (@ $I_{OH} = -8.0$ mA, V_{CC} min)	3.76		V
V_{OL}	Low-level output voltage (@ $I_{OL} = 8.0$ mA, V_{CC} min)		0.40	V
V_{CCPD}	Power-down supply voltage (PWRDWN must be Low)	2.30		V
I_{CCO}	Quiescent LCA supply current in addition to I_{CCPD}^1		8	mA
	Chip thresholds programmed as CMOS levels		14	mA
	Chip thresholds programmed as TTL levels			
I_{IL}	Input Leakage Current	-10	+10	μA
C_{IN}	Input capacitance, all packages except PGA175 (sample tested)		10	pF
	All Pins except XTL1 and XTL2		15	pF
	XTL1 and XTL2			
	Input capacitance, PGA 175 (sample tested)		15	pF
	All Pins except XTL1 and XTL2		20	pF
	XTL1 and XTL2			
I_{RIN}	Pad pull-up (when selected) @ $V_{IN} = 0$ V ³	0.02	0.17	mA
I_{RLL}	Horizontal Longline pull-up (when selected) @ logic Low	0.20	2.80	mA

- Notes:**
1. With no output current loads, no active input or Longline pull-up resistors, all package pins at V_{CC} or GND, and the LCA device configured with a tie option.
 2. Total continuous output sink current may not exceed 100 mA per ground pin. The number of ground pins varies from two for the XC3120A in the PC84 package, to eight for the XC3195A in the PQ208 package.
 3. Not tested. Allows an undriven pin to float High. For any other purpose, use an external pull-up.

XC3100A Absolute Maximum Ratings

Symbol	Description		Units
V_{CC}	Supply voltage relative to GND	-0.5 to +7.0	V
V_{IN}	Input voltage with respect to GND	-0.5 to $V_{CC} + 0.5$	V
V_{TS}	Voltage applied to 3-state output	-0.5 to $V_{CC} + 0.5$	V
T_{STG}	Storage temperature (ambient)	-65 to +150	°C
T_{SOL}	Maximum soldering temperature (10 s @ 1/16 in.)	+260	°C
T_J	Junction temperature plastic	+125	°C
	Junction temperature ceramic	+150	°C

Note: Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those listed under Recommended Operating Conditions is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time may affect device reliability.

XC3100A Global Buffer Switching Characteristics Guidelines

Speed Grade		-4	-3	-2	-1	-09	Units
Description	Symbol	Max	Max	Max	Max	Max	
Global and Alternate Clock Distribution¹							
Either: Normal IOB input pad through clock buffer to any CLB or IOB clock input	T _{PID}	6.5	5.6	4.7	4.3	3.9	ns
Or: Fast (CMOS only) input pad through clock buffer to any CLB or IOB clock input	T _{PIDC}	5.1	4.3	3.7	3.5	3.1	ns
TBUF driving a Horizontal Longline (L.L.)¹							
I to L.L. while T is Low (buffer active) (XC3100)	T _{IO}	3.7	3.1				ns
(XC3100A)	T _{IO}	3.6	3.1	3.1	2.9	2.1	ns
T↓ to L.L. active and valid with single pull-up resistor	T _{ON}	5.0	4.2	4.2	4.0	3.1	ns
T↓ to L.L. active and valid with pair of pull-up resistors	T _{ON}	6.5	5.7	5.7	5.5	4.6	ns
T↑ to L.L. High with single pull-up resistor	T _{PUS}	13.5	11.4	11.4	10.4	8.9	ns
T↑ to L.L. High with pair of pull-up resistors	T _{PUF}	10.5	8.8	8.1	7.1	5.9	ns
BIDI							
Bidirectional buffer delay	T _{BIDI}	1.2	1.0	0.9	0.85	0.75	ns
							Prelim

Prelim

Note: 1. Timing is based on the XC3142A, for other devices see timing calculator.
The use of two pull-up resistors per longline, available on other XC3000 devices, is not a valid design option for XC3100A devices.

XC3100A IOB Switching Characteristics Guidelines

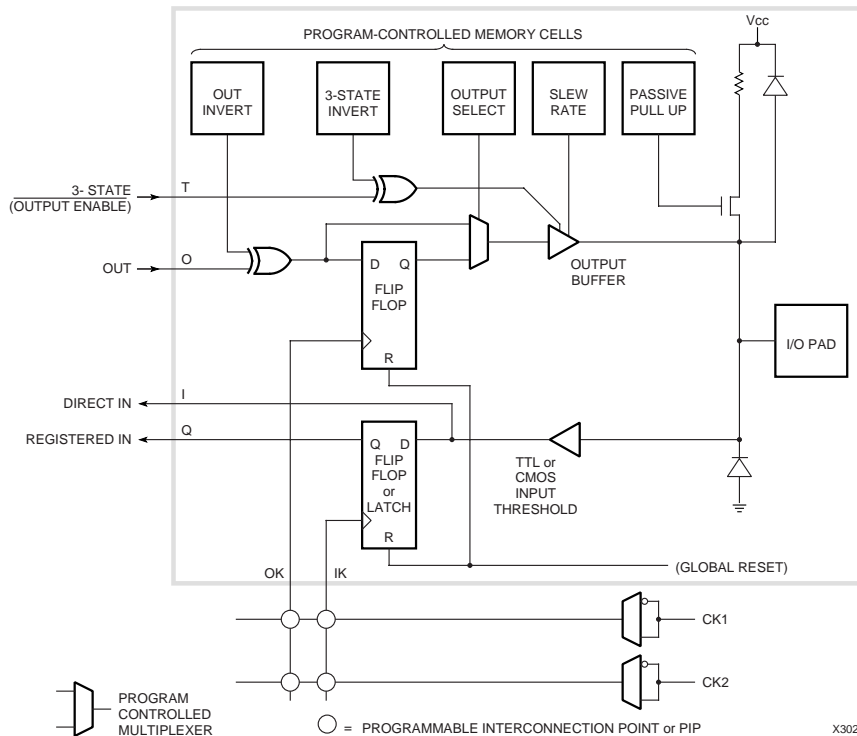
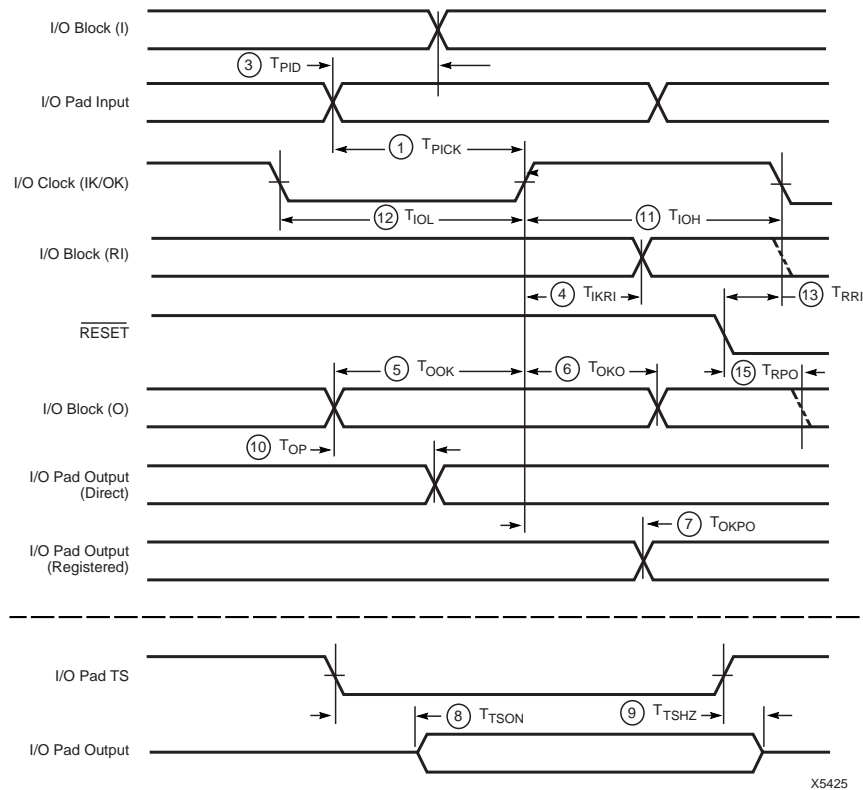
Testing of the switching parameters is modeled after testing methods specified by MIL-M-38510/605. All devices are 100% functionally tested. Since many internal timing parameters cannot be measured directly, they are derived from benchmark timing patterns. The following guidelines reflect worst-case values over the recommended operating conditions. For more detailed, more precise, and more up-to-date timing information, use the values provided by the timing calculator and used in the simulator.

Speed Grade			-4		-3		-2		-1		-09		Units
Description	Symbol		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
Propagation Delays (Input)													
Pad to Direct In (I)	3	T _{PID}		2.5		2.2		2.0		1.7		1.55	ns
Pad to Registered In (Q)													
with latch transparent(XC3100A)Clock (IK)		T _{PTG}		12.0		11.0		11.0		10.0		9.2	ns
to Registered In (Q)	4	T _{IKRI}		2.5		2.2		1.9		1.7		1.55	ns
Set-up Time (Input)													
Pad to Clock (IK) set-up time													
XC3120A, XC3130A	1	T _{PICK}	10.6		9.4		8.9		8.0		7.2		ns
XC3142A			10.7		9.5		9.0		8.1		7.3		ns
XC3164A			11.0		9.7		9.2		8.3		7.5		ns
XC3190A			11.2		9.9		9.4		8.5		7.7		ns
XC3195A			11.6		10.3		9.8		8.9		8.1		ns
Propagation Delays (Output)													
Clock (OK) to Pad (fast)	7	T _{OKPO}		5.0		4.4		3.7		3.4		3.3	ns
same (slew rate limited)	7	T _{OKPO}		12.0		10.0		9.7		8.4		6.9	ns
Output (O) to Pad (fast)	10	T _{OPF}		3.7		3.3		3.0		3.0		2.9	ns
same (slew-rate limited)													ns
(XC3100A)	10	T _{OPS}		11.0		9.0		8.7		8.0		6.5	ns
3-state to Pad													
begin hi-Z (fast)	9	T _{TSHZ}		6.2		5.5		5.0		4.5		4.05	ns
same (slew-rate limited)	9	T _{TSHZ}		6.2		5.5		5.0		4.5		4.05	ns
3-state to Pad													
active and valid (fast) (XC3100A)	8	T _{TSO}		10.0		9.0		8.5		6.5		5.0	ns
same (slew -rate limited)	8	T _{TSO}		17.0		15.0		14.2		11.5		8.6	ns
Set-up and Hold Times (Output)													
Output (O) to clock (OK) set-up time (XC3100A)	5	T _{OOK}	4.5				3.6		3.2		2.9		ns
Output (O) to clock (OK) hold time	6	T _{OKO}	0				0		0				ns
Clock													
Clock High time	11	T _{IOH}	2.0		1.6		1.3		1.3		1.3		ns
Clock Low time	12	T _{IOL}	2.0		1.6		1.3		1.3		1.3		ns
Max. flip-flop toggle rate		F _{CLK}	227		270		323		323		370		MHz
Global Reset Delays													
RESET Pad to Registered In (Q)													
(XC3142A)	13	T _{RR}		15.0		13.0		13.0		13.0		14.4	ns
(XC3190A)				25.5		21.0		21.0		21.0		21.0	ns
RESET Pad to output pad (fast)	15	T _{RPO}		20.0		17.0		17.0		17.0		17.0	ns
(slew-rate limited)	15	T _{RPO}		27.0		23.0		23.0		22.0		21.0	ns

Preliminary

- Notes:**
1. Timing is measured at pin threshold, with 50 pF external capacitive loads (incl. test fixture). For larger capacitive loads, see XAPP024. Typical slew rate limited output rise/fall times are approximately four times longer.
 2. Voltage levels of unused (bonded and unbonded) pads must be valid logic levels. Each can be configured with the internal pull-up resistor or alternatively configured as a driven output or driven from an external source.
 3. Input pad set-up time is specified with respect to the internal clock (ik). In order to calculate system set-up time, subtract clock delay (pad to ik) from the input pad set-up time value. Input pad holdtime with respect to the internal clock (ik) is negative. This means that pad level changes immediately before the internal clock edge (ik) will not be recognized.
 4. T_{PID}, T_{PTG}, and T_{PICK} are 3 ns higher for XTL2 when the pin is configured as a user input.

XC3100A IOB Switching Characteristics Guidelines (continued)



XC3100L Switching Characteristics

Xilinx maintains test specifications for each product as controlled documents. To insure the use of the most recently released device performance parameters, please request a copy of the current test-specification revision.

XC3100L Operating Conditions

Symbol	Description	Min	Max	Units
V_{CC}	Supply voltage relative to GND Commercial 0°C to +85°C junction	3.0	3.6	V
V_{IH}	High-level input voltage	2.0	$V_{CC} + 0.3$	V
V_{IL}	Low-level input voltage	-0.3	0.8	V
T_{IN}	Input signal transition time		250	ns

- Notes:** 1. At junction temperatures above those listed as Operating Conditions, all delay parameters increase by 0.3% per °C.
2. Although the present (1996) devices operate over the full supply voltage range from 3.0 V to 5.25 V, Xilinx reserves the right to restrict operation to the 3.0 and 3.6 V range later, when smaller device geometries might preclude operation @ 5 V. Operating conditions are guaranteed in the 3.0 – 3.6 V V_{CC} range.

XC3100L DC Characteristics Over Operating Conditions

Symbol	Description	Min	Max	Units
V_{OH}	High-level output voltage (@ $I_{OH} = -4.0$ mA, V_{CC} min)	2.4		V
	High-level output voltage (@ $I_{OH} = -100.0$ μ A, V_{CC} min)	$V_{CC} - 0.2$		V
V_{OL}	Low-level output voltage (@ $I_{OH} = 4.0$ mA, V_{CC} min)		0.40	V
	Low-level output voltage (@ $I_{OH} = +100.0$ μ A, V_{CC} min)		0.2	V
V_{CCPD}	Power-down supply voltage (PWRDWN must be Low)	2.30		V
I_{CCO}	Quiescent FPGA supply current Chip thresholds programmed as CMOS levels ¹		1.5	mA
I_{IL}	Input Leakage Current	-10	+10	μ A
C_{IN}	Input capacitance (sample tested) All pins except XTL1 and XTL2		10	pF
	XTL1 and XTL2		15	pF
I_{RIN}	Pad pull-up (when selected) @ $V_{IN} = 0$ V ³	0.02	0.17	mA
I_{RLL}	Horizontal long line pull-up (when selected) @ logic Low	0.20	2.80	mA

- Notes:** 1. With no output current loads, no active input or long line pull-up resistors, all package pins at V_{CC} or GND, and the FPGA configured with a tie option.
2. Total continuous output sink current may not exceed 100 mA per ground pin. Total continuous output source current may not exceed 100 mA per V_{CC} pin. The number of ground pins varies from the XC3142L to the XC3190L.
3. Not tested. Allows undriven pins to float High. For any other purpose, use an external pull-up.

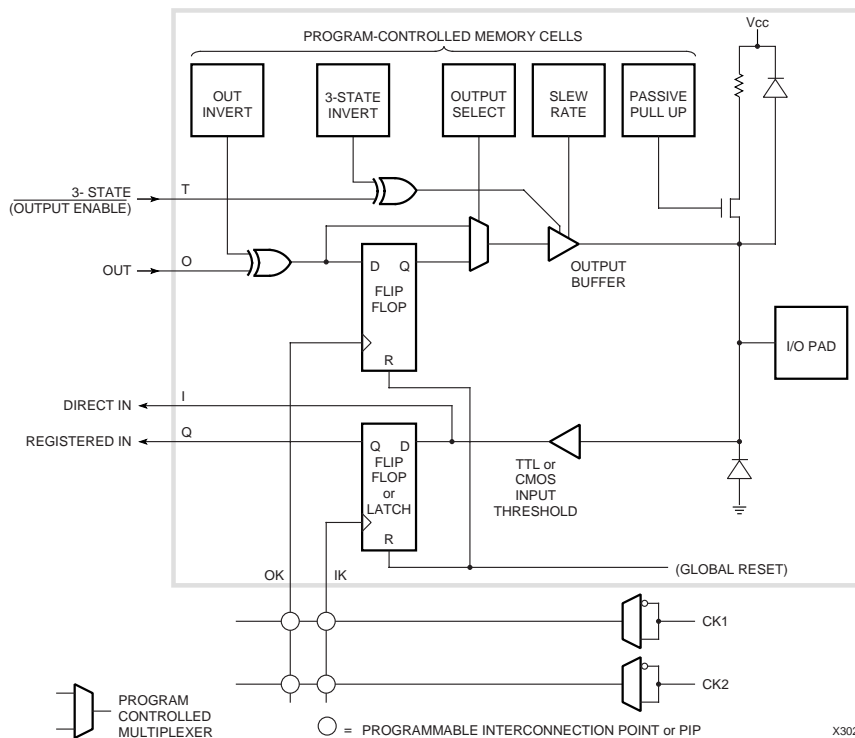
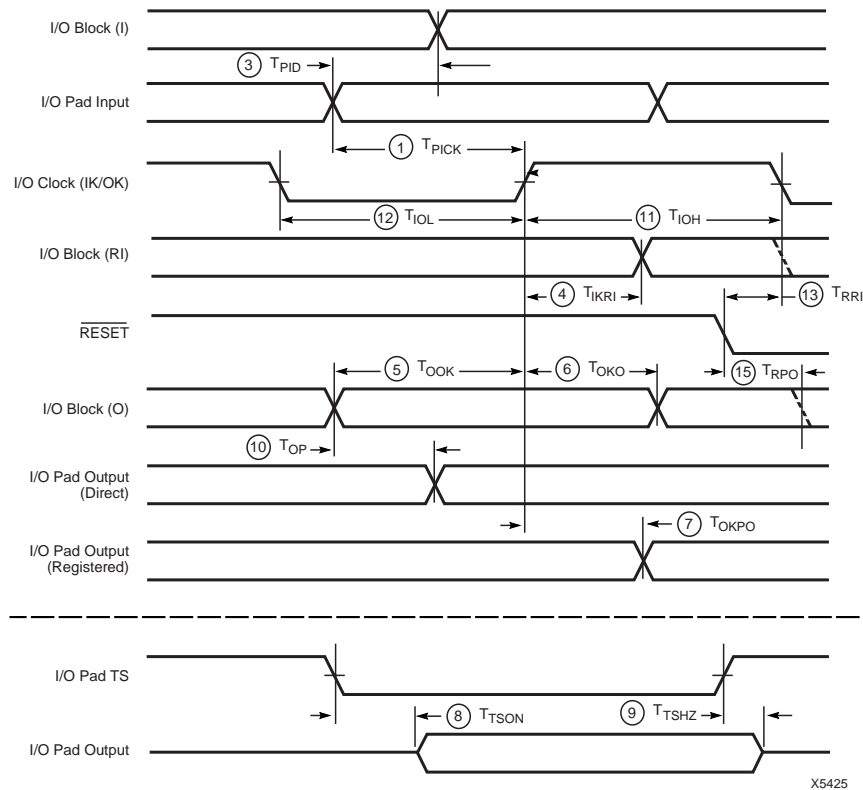
XC3100L IOB Switching Characteristics Guidelines

Testing of the switching parameters is modeled after testing methods specified by MIL-M-38510/605. All devices are 100% functionally tested. Since many internal timing parameters cannot be measured directly, they are derived from benchmark timing patterns. The following guidelines reflect worst-case values over the recommended operating conditions. For more detailed, more precise, and more up-to-date timing information, use the values provided by the timing calculator and used in the simulator.

		Speed Grade	-3		-2		
Description	Symbol		Min	Max	Min	Max	Units
Propagation Delays (Input)							
Pad to Direct In (I)	3	T_{PID}		2.2		2.0	ns
Pad to Registered In (Q) with latch (XC3100L) transparent		T_{PTG}		11.0		11.0	ns
Clock (IK) to Registered In (Q)	4	T_{IKRI}		2.2		1.9	ns
Set-up Time (Input)							
Pad to Clock (IK) set-up time	1	T_{PICK}					
XC3142L			9.5		9.0		ns
XC3190L			9.9		9.4		ns
Propagation Delays (Output)							
Clock (OK) to Pad (fast)	7	T_{OKPO}		4.4		4.0	ns
same (slew rate limited)	7	T_{PO}		10.0		9.7	ns
Output (O) to Pad (fast)	10	T_{OPF}		3.3		3.0	ns
same (slew-rate limited)(XC3100L)	10	T_{OPF}		9.0		8.7	ns
3-state to Pad begin hi-Z (fast)	9	T_{TSHZ}		5.5		5.0	ns
same (slew-rate limited)	9	T_{TSHZ}		5.5		5.0	ns
3-state to Pad active and valid (fast)(XC3100L)	8	T_{TSOIN}		9.0		8.5	ns
same (slew -rate limited)	8	T_{TSOIN}		15.0		14.2	ns
Set-up and Hold Times (Output)							
Output (O) to clock (OK) set-up time (XC3100L)	5	T_{OOK}	4.0		3.6		ns
Output (O) to clock (OK) hold time	6	T_{OKO}	0		0		ns
Clock							
Clock High time	11	T_{IOH}	1.6		1.3		ns
Clock Low time	12	T_{IOL}	1.6		1.3		ns
Export Control Maximum flip-flop toggle rate		F_{TOG}	270		325		MHz
Global Reset Delays							
RESET Pad to Registered In (Q)							
(XC3142L)	13	T_{RRI}		16.0		16.0	ns
(XC3190L)				21.0		21.0	ns
RESET Pad to output pad (fast)	15	T_{RPO}		17.0		17.0	ns
(slew-rate limited)	15	T_{RPO}		23.0		23.0	ns
Advance							

- Notes:**
1. Timing is measured at pin threshold, with 50 pF external capacitive loads (incl. test fixture). Typical slew rate limited output rise/fall times are approximately four times longer.
 2. Voltage levels of unused (bonded and unbonded) pads must be valid logic levels. Each can be configured with the internal pull-up resistor or alternatively configured as a driven output or driven from an external source.
 3. Input pad set-up time is specified with respect to the internal clock (IK). In order to calculate system set-up time, subtract clock delay (pad to ik) from the input pad set-up time value. Input pad holdtime with respect to the internal clock (IK) is negative. This means that pad level changes immediately before the internal clock edge (IK) will not be recognized.

XC3100L IOB Switching Characteristics Guidelines (continued)



Product Obsolete or Under Obsolescence



XC3000 Series Field Programmable Gate Arrays

XC3000 Series 144-Pin Plastic TQFP Pinouts

XC3000A, XC3000L, XC3100A, and XC3100L families have identical pinouts

Pin Number	XC3042A XC3064A XC3090A	Pin Number	XC3042A XC3064A XC3090A	Pin Number	XC3042A XC3064A XC3090A
1	PWRDN	49	I/O	97	I/O
2	I/O-TCLKIN	50	I/O*	98	I/O
3	I/O*	51	I/O	99	I/O*
4	I/O	52	I/O	100	I/O
5	I/O	53	INIT-I/O	101	I/O*
6	I/O*	54	VCC	102	D1-I/O
7	I/O	55	GND	103	RDY/BUSY-RCLK-I/O
8	I/O	56	I/O	104	I/O
9	I/O*	57	I/O	105	I/O
10	I/O	58	I/O	106	D0-DIN-I/O
11	I/O	59	I/O	107	DOOUT-I/O
12	I/O	60	I/O	108	CCLK
13	I/O	61	I/O	109	VCC
14	I/O	62	I/O	110	GND
15	I/O*	63	I/O*	111	A0-WS-I/O
16	I/O	64	I/O*	112	A1-CS2-I/O
17	I/O	65	I/O	113	I/O
18	GND	66	I/O	114	I/O
19	VCC	67	I/O	115	A2-I/O
20	I/O	68	I/O	116	A3-I/O
21	I/O	69	XTL2(IN)-I/O	117	I/O
22	I/O	70	GND	118	I/O
23	I/O	71	RESET	119	A15-I/O
24	I/O	72	VCC	120	A4-I/O
25	I/O	73	DONE-PG	121	I/O*
26	I/O	74	D7-I/O	122	I/O*
27	I/O	75	XTL1(OUT)-BCLKIN-I/O	123	A14-I/O
28	I/O*	76	I/O	124	A5-I/O
29	I/O	77	I/O	125	I/O (XC3090 only)
30	I/O	78	D6-I/O	126	GND
31	I/O*	79	I/O	127	VCC
32	I/O*	80	I/O*	128	A13-I/O
33	I/O	81	I/O	129	A6-I/O
34	I/O*	82	I/O	130	I/O*
35	I/O	83	I/O*	131	I/O (XC3090 only)
36	M1-RD	84	D5-I/O	132	I/O*
37	GND	85	CS0-I/O	133	A12-I/O
38	M0-RT	86	I/O*	134	A7-I/O
39	VCC	87	I/O*	135	I/O
40	M2-I/O	88	D4-I/O	136	I/O
41	HDC-I/O	89	I/O	137	A11-I/O
42	I/O	90	VCC	138	A8-I/O
43	I/O	91	GND	139	I/O
44	I/O	92	D3-I/O	140	I/O
45	LDC-I/O	93	CS1-I/O	141	A10-I/O
46	I/O*	94	I/O*	142	A9-I/O
47	I/O	95	I/O*	143	VCC
48	I/O	96	D2-I/O	144	GND

Unprogrammed IOBs have a default pull-up. This prevents an undefined pad level for unbonded or unused IOBs. Programmed outputs are default slew-rate limited.

* Indicates unconnected package pins (24) for the XC3042A.

Product Obsolete or Under Obsolescence



XC3000 Series Field Programmable Gate Arrays

Product Availability

Pins		44	64	68	84		100			132		144	160	175		176	208
Type		Plast. PLCC	Plast. VQFP	Plast. PLCC	Plast. PLCC	Cer. PGA	Plast. PQFP	Plast. TQFP	Plast. VQFP	Plast. PGA	Cer. PGA	Plast. TQFP	Plast. PQFP	Plast. PGA	Cer. PGA	Plast. TQFP	Plast. PQFP
Code		PC44	VQ64	PC68	PC84	PG84	PQ100	TQ100	VQ100	PP132	PG132	TQ144	PQ160	PP175	PG175	TQ176	PQ208
XC3020A	-7			CI	CI		CI										
	-6			C	C		C										
XC3030A	-7	CI	CI	CI	CI		CI		CI								
	-6	C	C	C	C		C		C								
XC3042A	-7				CI	CI	CI		CI		CI	CI					
	-6				C	C	C		C		C	C					
XC3064A	-7				CI					CI	CI	CI	CI				
	-6				C					C	C	C	C				
XC3090A	-7				CI							CI	CI	CI	CI	CI	CI
	-6				C							C	C	C	C	C	C
XC3020L	-8				CI												
XC3030L	-8		CI		CI				CI								
XC3042L	-8				CI				CI			CI					
XC3064L	-8				CI							CI					
XC3090L	-8				CI							CI				CI	
XC3120A	-4			CI	CI		CI										
	-3			CI	CI		CI										
	-2			CI	CI		CI										
	-1			C	C		C										
	-09			C	C		C										
XC3130A	-4	CI	CI	CI	CI		CI		CI								
	-3	CI	CI	CI	CI		CI		CI								
	-2	CI	CI	CI	CI		CI		CI								
	-1	C	C	C	C		C		C								
	-09	C	C	C	C		C		C								
XC3142A	-4				CI		CI		C			CI					
	-3				CI		CI		CI			CI					
	-2				CI		CI		CI			CI					
	-1				C		C		C			C					
	-09				C		C		C			C					
XC3164A	-4				CI							CI	CI				
	-3				CI							CI	CI				
	-2				CI							CI	CI				
	-1				C							C	C				
	-09				C							C	C				
XC3190A	-4				CI							CI	CI	CI	CI	CI	CI
	-3				CI							CI	CI	CI	CI	CI	CI
	-2				CI							CI	CI	CI	CI	CI	CI
	-1				C							C	C	C	C	C	C
	-09				C							C	C	C	C	C	C
XC3195A	-4				CI								CI	CI	CI		CI
	-3				CI								CI	CI	CI		CI
	-2				CI								CI	CI	CI		CI
	-1				C								C	C	C		C
	-09				C								C	C	C		C